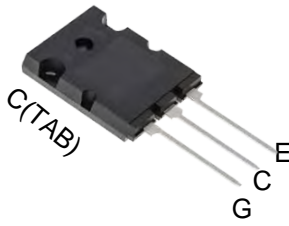


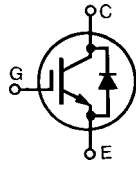
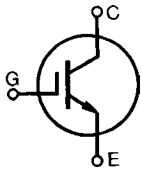
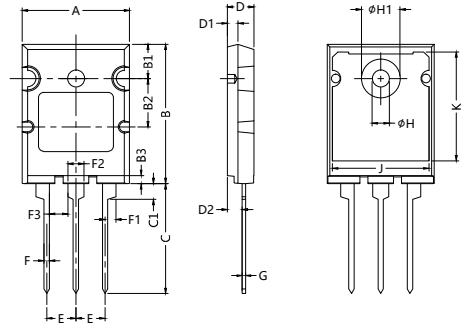
SG100T65UDB3

Discrete IGBTs



G=Gate,
C=Collector,
E=Emitter,
TAB=Collector

Dimensions TO-264



SG100T65UB3

SG100T65UDB3



MAXIMUM RATING (Ta=25 °C)

CHARACTERISTIC	SYMBOL	RATING	UNIT	
Collector-Emitter Voltage	V_{CES}	650	V	
Gate-Emitter Voltage	V_{GES}	±20	V	
Collector Current	I_C	@Tc=25°C	120	A
		@Tc=100°C	100	A
Pulsed Collector Current	I_{CM}^*	250	A	
Diode Continuous Forward	@Tc=100°C	I_F	100	A
Current Diode Maximum	I_{FM}	200	A	
Maximum Power Dissipation	P_D	@Tc=25°C	520	W
		@Tc=100°C	260	W
Maximum Junction Temperature	T_j	175	°C	
Storage Temperature Range	T_{stg}	-55 to +150	°C	

*

Repetitive rating : Pulse width limited by max. junction temperature

THERMAL CHARACTERISTIC

CHARACTERISTIC	SYMBOL	MAX.	UNIT
Thermal Resistance, Junction to Case	R_{thJC}	0.19	°C/W
(IGBT) Thermal Resistance, Junction to Case	R_{thJC}	0.62	°C/W
(DIODE) Thermal Resistance, Junction to Ambient	R_{thJA}	31	°C/W

General Description

SIRECTIFIER Trench Field Stop IGBTs offer low switching losses, high energy efficiency and short circuit ruggedness.

It is designed for applications such as motor control, uninterrupted power supplies(UPS), general inverters.

FEATURES

- High speed switching
- High ruggedness, temperature stable behavior
- Short Circuit Withstand Times 10us
- Extremely enhanced avalanche capability

SG100T65UDB3

Discrete IGBTs

ELECTRICAL CHARACTERISTICS (Ta=25 °C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Static							
Collector-Emitter Breakdown Voltage	BV _{CES}	V _{GE} =0V, I _C =250μA	650		-	V	
Collector Cut-off Current	I _{CES}	V _{GE} =0V, V _{CE} =600V	-	-	250	μA	
Gate Leakage Current	I _{GES}	V _{CE} =0V, V _{GE} =±20V	-	-	±100	nA	
Gate Threshold Voltage	V _{GE(th)}	V _{GE} =V _{CE} , I _C =7.5mA	5.0	6.0	7.5	V	
Collector-Emitter Saturation Voltage	V _{CE(sat)}	V _{GE} =15V, I _C =100A	-	1.85	2.20	V	
		V _{GE} =15V, I _C =200A	-	2.30	-	V	
		V _{GE} =15V, I _C =100A, T _C = 125°C	-	2.10	-	V	
Dynamic							
Total Gate Charge	Q _g	V _{CC} =300V, V _{GE} =15V, I _C = 100A	-	650	-	nC	
Gate-Emitter Charge	Q _{ge}		-	50	-	nC	
Gate-Collector Charge	Q _{gc}		-	140	-	nC	
Turn-On Delay Time	t _{d(on)}	V _{CC} =300V, I _C =100A, V _{GE} =15V, R _G =10Ω Inductive Load, T _C = 25°C (Note 1)	-	30	-	ns	
Rise Time	t _r		-	5€	-	ns	
Turn-Off Delay Time	t _{d(off)}		-	260	-	ns	
Turn-Off Delay Time	t _f		-	3Í	-	ns	
Turn-On Switching Loss	E _{on}		-	3.9	-	mJ	
Turn-Off Switching Loss	E _{off}		-	2.05	-	mJ	
Total Switching Loss	E _{ts}		-	5.95	-	mJ	
Turn-On Delay Time	t _{d(on)}		V _{CC} =300V, I _C =100A, V _{GE} =15V, R _G =10Ω Inductive Load, T _C = 125°C (Note 1)	-	30	-	ns
Rise Time	t _r			-	50	-	ns
Turn-Off Delay Time	t _{d(off)}			-	340	-	ns
Turn-Off Delay Time	t _f	-		30	-	ns	
Turn-On Switching Loss	E _{on}	-		5.0	-	mJ	
Turn-Off Switching Loss	E _{off}	-		2.35	-	mJ	
Total Switching Loss	E _{ts}	-		7.35	-	mJ	
Input Capacitance	C _{ies}	V _{CE} =30V, V _{GE} =0V, f=1MHz		-	6040	-	pF
Output Capacitance	C _{oes}		-	200	-	pF	
Reverse Transfer Capacitance	C _{res}		-	170	-	pF	
Short Circuit Withstand Time	t _{sc}	V _{CC} =300V, V _{GE} =15V, T _C =100°C	10	-	-	μs	

Note 1 : Energy loss include tail current and diode reverse recovery.



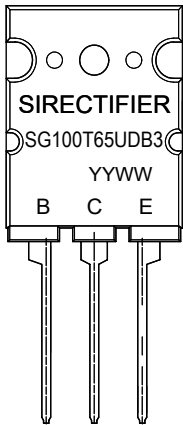
SG100T65UDB3

Discrete IGBTs

ELECTRICAL CHARACTERISTIC OF DIODE

CHARACTERISTIC	SYMBOL	TEST CONDITION		MIN.	TYP.	MAX.	UNIT
Diode Forward Voltage	V_F	$I_F = 100A$	$T_C = 25^\circ C$	-	1.75	2.1	V
			$T_C = 125^\circ C$	-	1.65	-	
Diode Reverse Recovery Time	t_{rr}	$V_{CC} = 300V,$ $I_F = 100A$	$T_C = 25^\circ C$	-	170	-	ns
			$T_C = 125^\circ C$	-	230	-	
Diode Peak Reverse Recovery Current	I_{rr}	$di/dt = 600A/\mu s$	$T_C = 25^\circ C$	-	25	-	A
			$T_C = 125^\circ C$	-	23	-	
Diode Reverse Recovery Charge	Q_{rr}		$T_C = 25^\circ C$	-	2.2	-	μC
			$T_C = 125^\circ C$	-	3.2	-	

MARKING



Company Logo
Part Number
Lot No.

ORDERING INFORMATION

Part Number	Package	Shipping	Marking Code
SG100T65UDB3	TO-264	20pcs / Tube	SG100T65UDB3

SG100T65UDB3

Discrete IGBTs

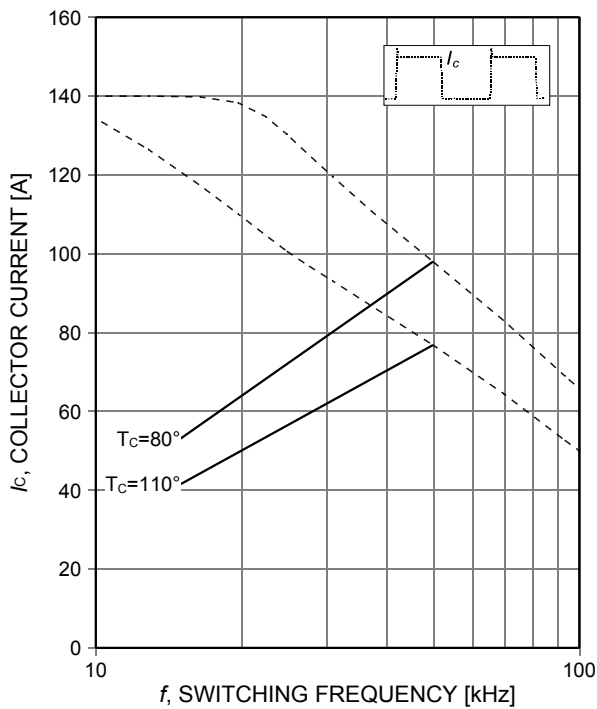


Figure 1. **Collector current as a function of switching frequency**
 ($T_{vj} \leq 175^\circ\text{C}$, $D=0.5$, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$,
 $r_G=3.5\Omega$, $R_{th(j-c)}=0.21\text{K/W}$)

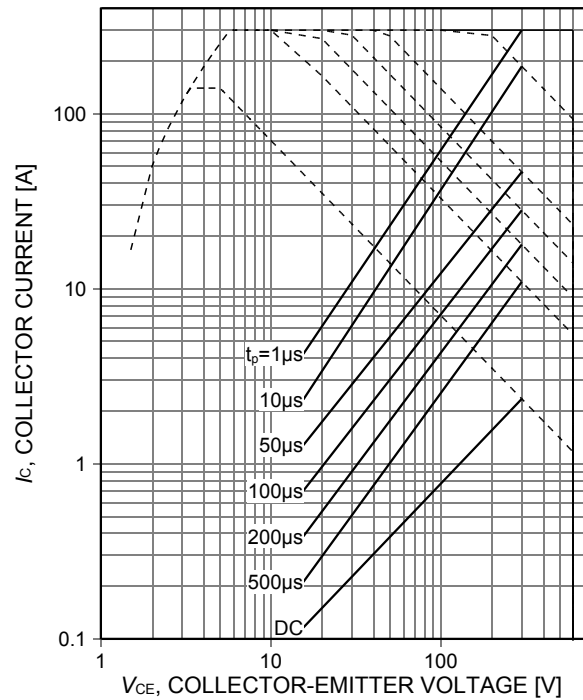


Figure 2. **Forward bias safe operating area**
 ($D=0$, $T_C=25^\circ\text{C}$, $T_{vj} \leq 175^\circ\text{C}$; $V_{GE}=15\text{V}$,
 $R_{th(j-c)}=0.21\text{K/W}$)

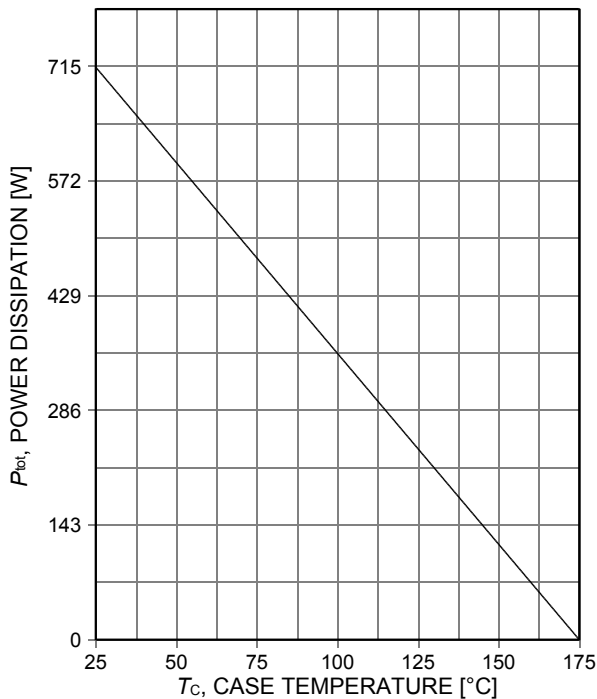


Figure 3. **Power dissipation as a function of case temperature**
 ($T_{vj} \leq 175^\circ\text{C}$, $R_{th(j-c)}=0.21\text{K/W}$)

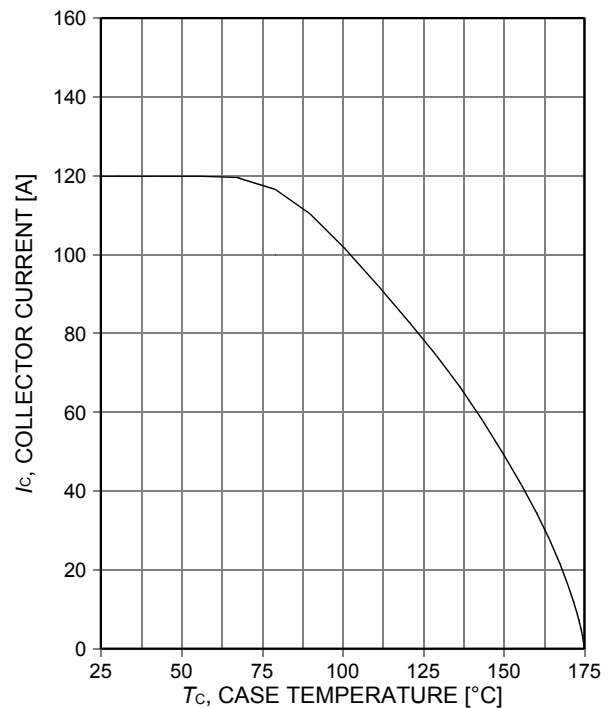


Figure 4. **Collector current as a function of case temperature**
 ($V_{GE} \geq 15\text{V}$, $T_{vj} \leq 175^\circ\text{C}$, $R_{th(j-c)}=0.21\text{K/W}$)

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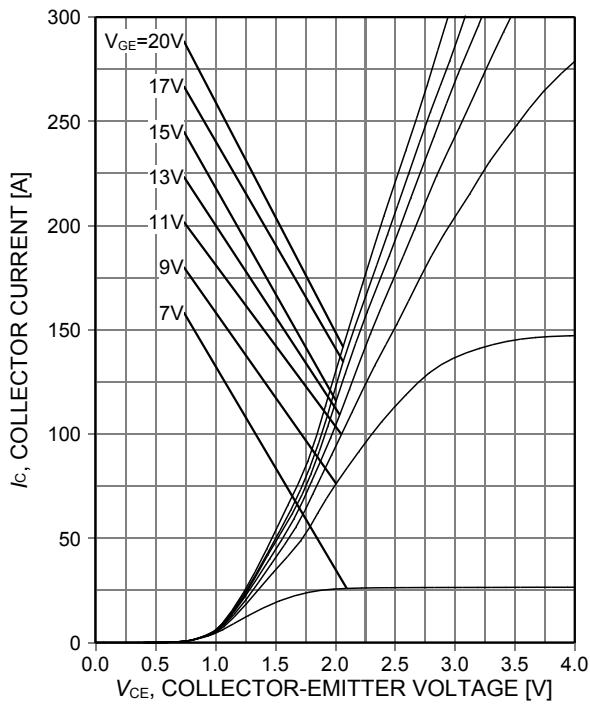


Figure 5. **Typical output characteristic**
($T_{vj}=25^{\circ}\text{C}$)

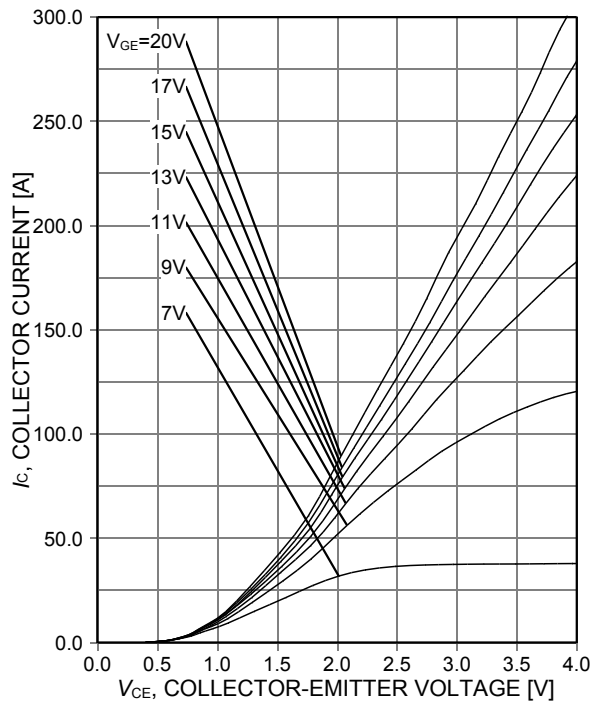


Figure 6. **Typical output characteristic**
($T_{vj}=175^{\circ}\text{C}$)

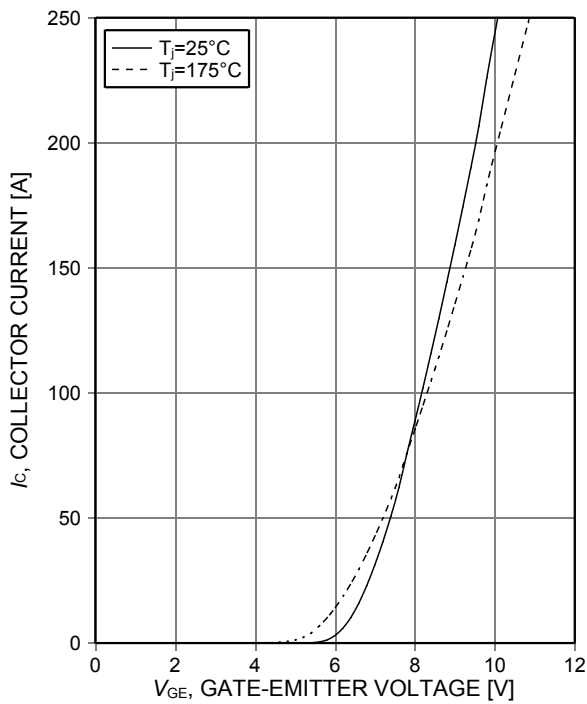


Figure 7. **Typical transfer characteristic**
($V_{CE}=20\text{V}$)

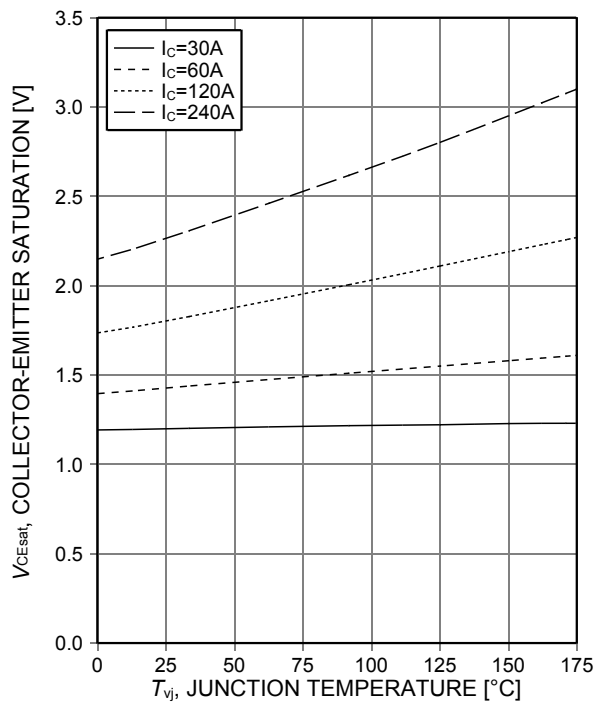


Figure 8. **Typical collector-emitter saturation voltage as a function of junction temperature**
($V_{GE}=15\text{V}$)

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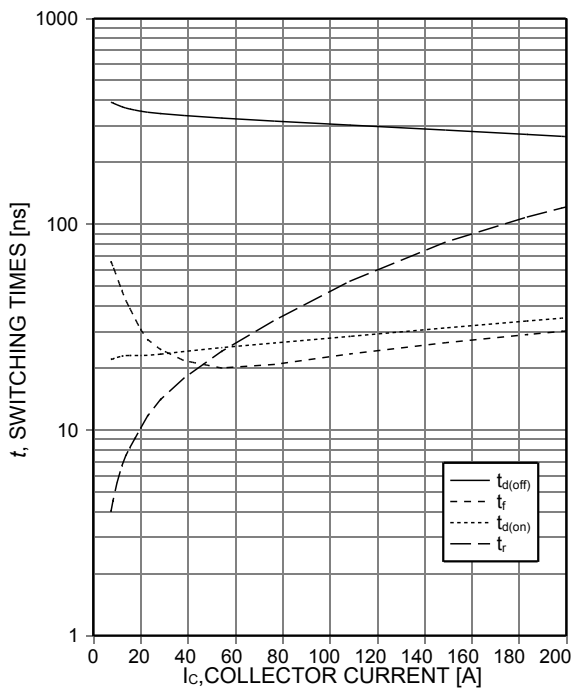


Figure 9. **Typical switching times as a function of collector current**
(inductive load, $T_{vj}=175^{\circ}\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $r_G=3.5\Omega$, Dynamic test circuit in Figure E)

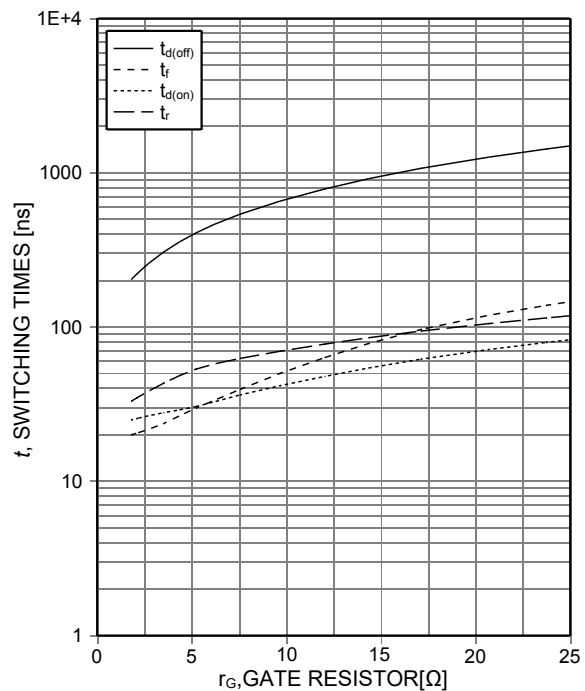


Figure 10. **Typical switching times as a function of gate resistor**
(inductive load, $T_{vj}=175^{\circ}\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $I_C=100\text{A}$, Dynamic test circuit in Figure E)

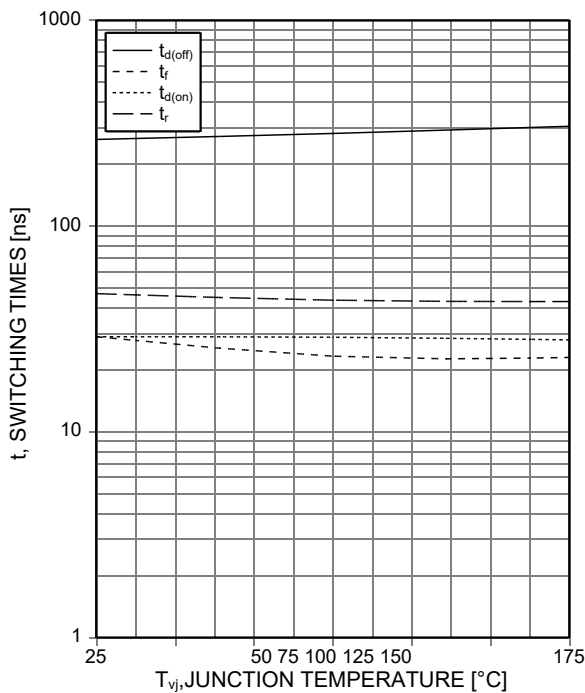


Figure 11. **Typical switching times as a function of junction temperature**
(inductive load, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $I_C=100\text{A}$, $r_G=3.5\Omega$, Dynamic test circuit in Figure E)

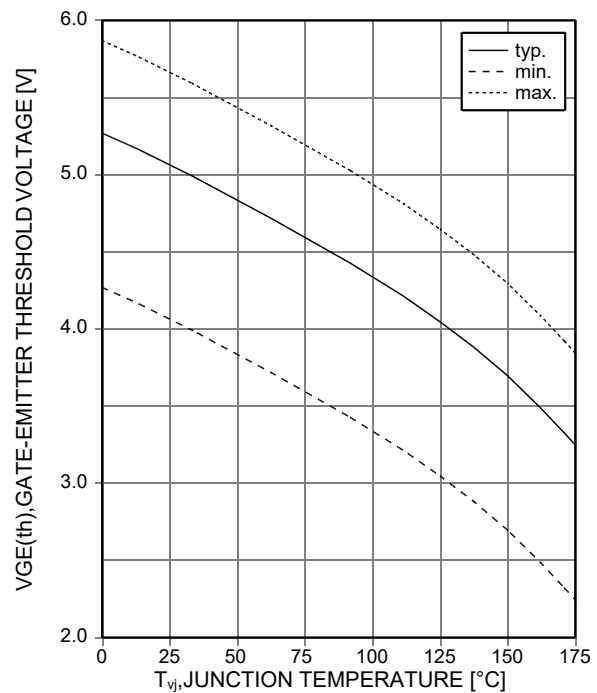


Figure 12. **Gate-emitter threshold voltage as a function of junction temperature**
($I_C=1.6\text{mA}$)

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Discrete IGBTs

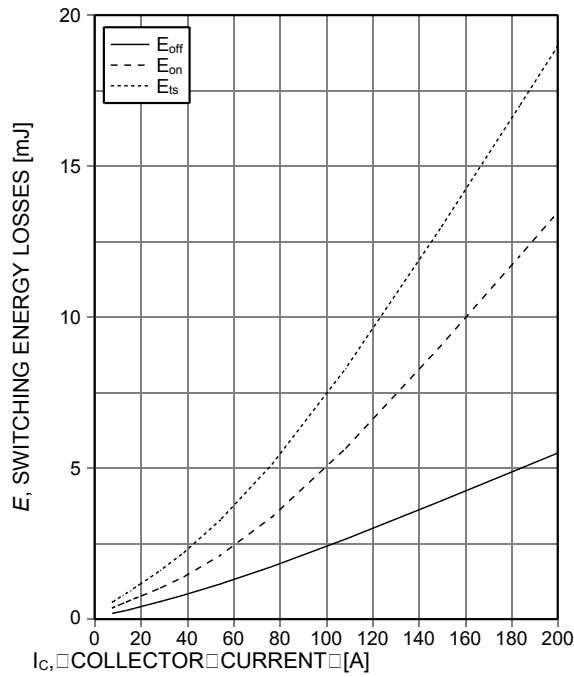


Figure 13. **Typical switching energy losses as a function of collector current** (inductive load, $T_{vj}=175^{\circ}\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $r_G=3.5\Omega$, Dynamic test circuit in Figure E)

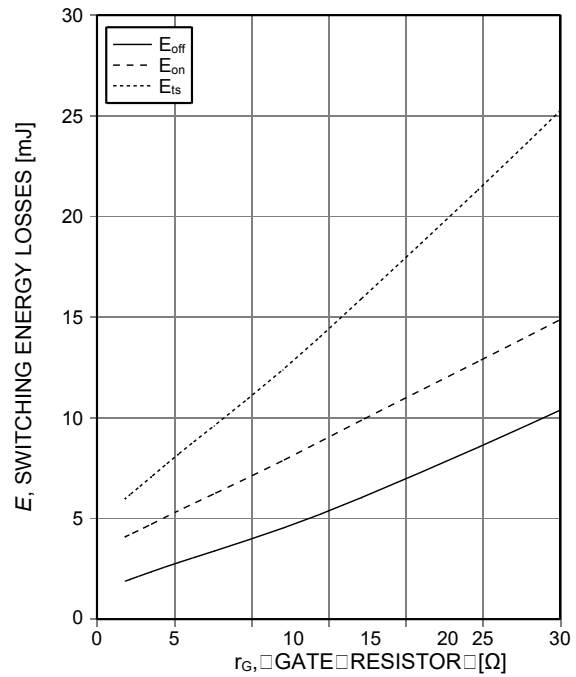


Figure 14. **Typical switching energy losses as a function of gate resistor** (inductive load, $T_{vj}=175^{\circ}\text{C}$, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $I_C=100\text{A}$, Dynamic test circuit in Figure E)

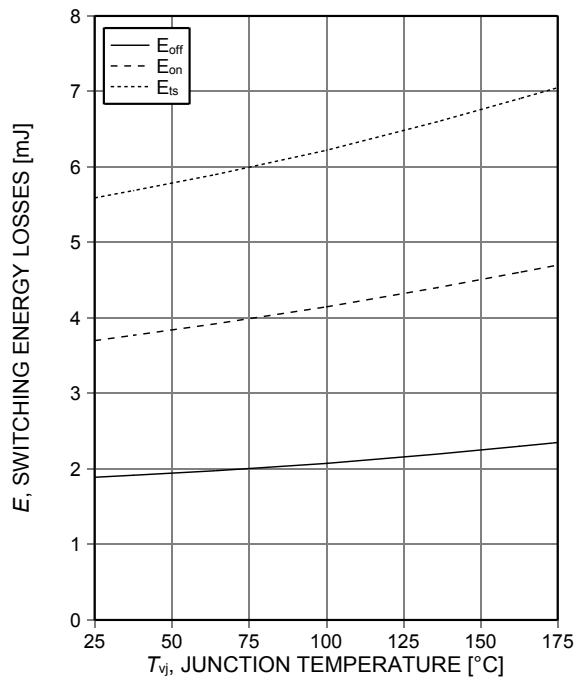


Figure 15. **Typical switching energy losses as a function of junction temperature** (inductive load, $V_{CE}=400\text{V}$, $V_{GE}=15/0\text{V}$, $I_C=100\text{A}$, $r_G=3.5\Omega$, Dynamic test circuit in Figure E)

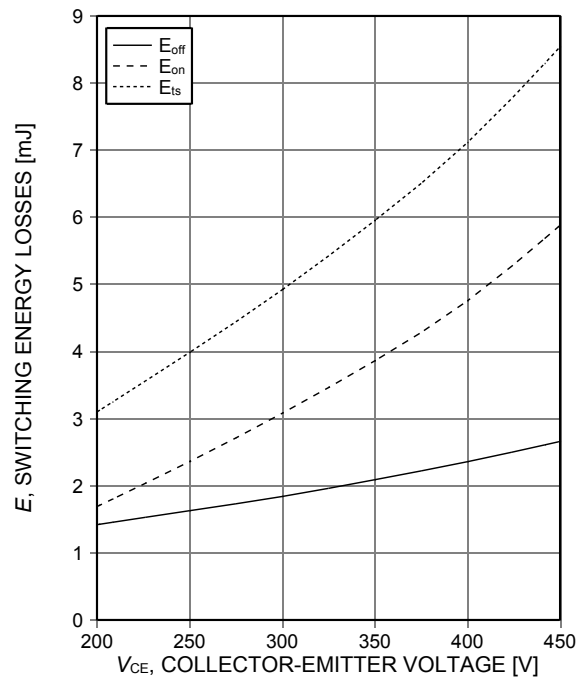


Figure 16. **Typical switching energy losses as a function of collector-emitter voltage** (inductive load, $T_{vj}=175^{\circ}\text{C}$, $V_{GE}=15/0\text{V}$, $I_C=100\text{A}$, $r_G=3.5\Omega$, Dynamic test circuit in Figure E)

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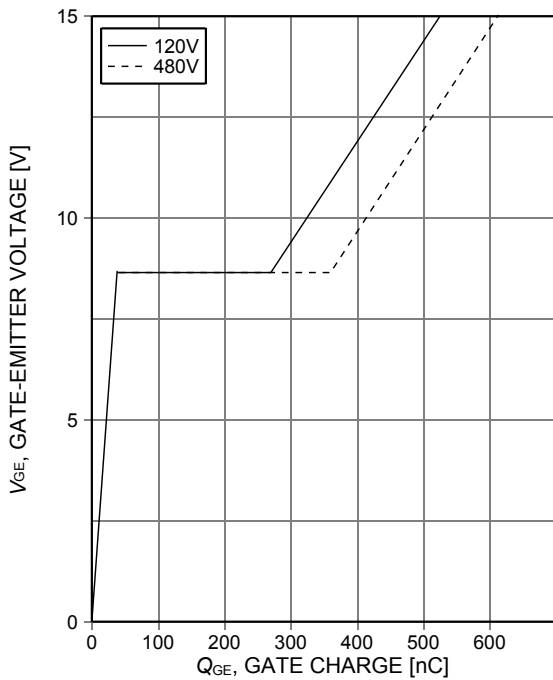


Figure 17. **Typical gate charge**
($I_c=100A$)

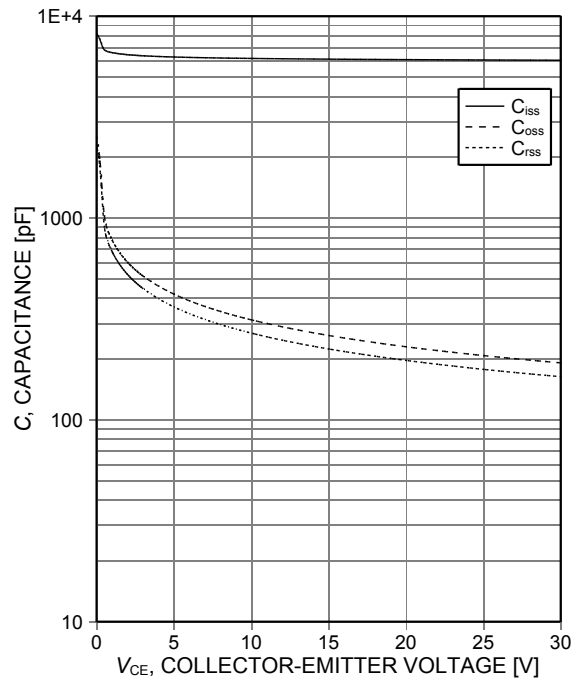


Figure 18. **Typical capacitance as a function of collector-emitter voltage**
($V_{GE}=0V$, $f=1MHz$)

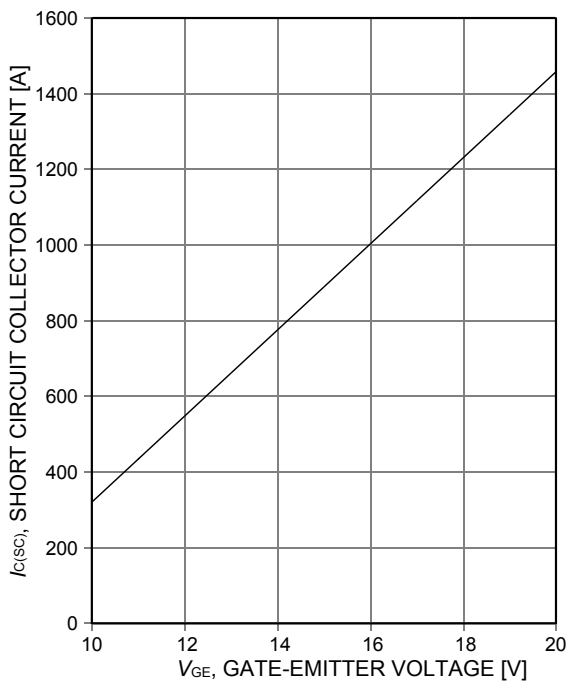


Figure 19. **Typical short circuit collector current as a function of gate-emitter voltage**
($V_{CE}\leq 400V$, $T_{vj}\leq 150^\circ C$)

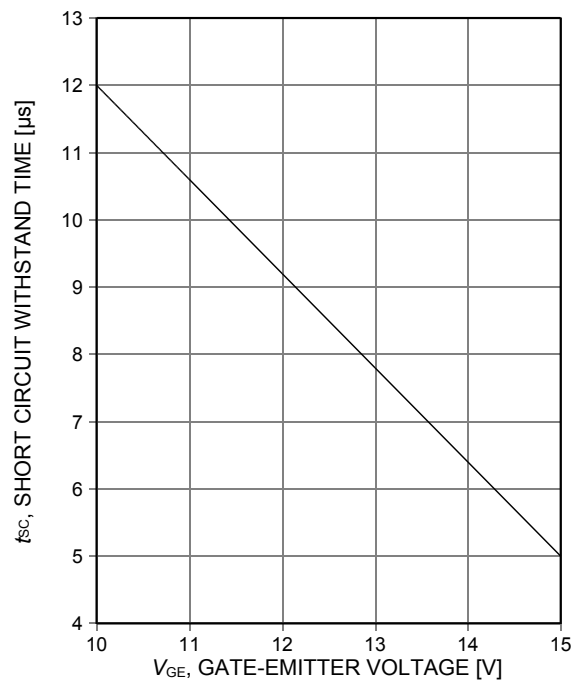


Figure 20. **Short circuit withstand time as a function of gate-emitter voltage**
($V_{CE}\leq 400V$, start at $T_{vj}\leq 150^\circ C$)